



MEAD Education S.A.

Techniques for Handling Noise and Variability in Analog Circuits

**EPFL PREMISES, LAUSANNE, SWITZERLAND
JANUARY 18-22, 2016**

MONDAY, January 18

| | | |
|---------------|---|----------------|
| 8:30-12:00 am | Fundamentals of Noise in Electronic Devices | Christian Enz |
| 1:30-5:00 pm | Random Mismatch Origins | Marcel Pelgrom |

TUESDAY, January 19

| | | |
|---------------|---|----------------|
| 8:30-12:00 am | Noise Analysis in Continuous-Time and Sampled-Data Circuits | Christian Enz |
| 1:30-5:00 pm | Analyzing Mismatch and Yield in Analog Circuits | Marcel Pelgrom |

WEDNESDAY, January 20

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|----------------|--|--------------|
| 8:30-10:00 am | Noise Cancellation Techniques | Willy Sansen |
| 10:30-12:00 am | Noise Sampling in Switched Capacitor Filters | Willy Sansen |
| 1:30-3:00 pm | Offset, CMRR and PSRR | Willy Sansen |
| 3:30-5:00 pm | Variability in Bandgaps | Willy Sansen |

THURSDAY, January 21

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|---------------|---|----------------|
| 8:30-12:00 am | Layout Strategies to Reduce Offset | Marcel Pelgrom |
| 1:30-5:00 pm | Noise and Mismatch Mitigation on Transistor-Level (Auto-Zero, Chopping) | Kofi Makinwa |

FRIDAY, January 22

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|-------------------------------|---|--------------|
| 8:30-10:00 am | DEM | Kofi Makinwa |
| 10:30-12:00 am & 1:30-3:00 pm | gm/Id Methodology for Autozero Calibration of Analog Circuits and Systems | Maher Kayal |
